Kaleo Kit Fully modular metrology solution from UV to IR





ASSEMBLE YOUR OWN MODULAR METROLOGY SYSTEM...

With the rise in complexity of optical systems, metrology teams often need **specific measurement parameters** (test wavelength, accuracy, resolution, relevant outcomes...). PHASICS answers this challenge with **Kaleo Kit**, its modular system for optics qualification.

Kaleo Kit is the combination of a broad range of compatible modules, that let you create a **cost-effective, compact, and easy-to-use system** that can adapt to a wide range of measurement configurations and ensure the quality of your sample at all development stages.

Access all the characteristics of your sample in a **single shot acquisition**: TWE, RWE, wavefront aberrations, MTF, PSF, and a lot more!



PHASICS - the phase control company

... IN JUST 3 EASY STEPS

Choose YOUR Wavefront Sensor

SID4	Spectral Range	Sampling
Model	(nm)	(px)
SID4-UV	250-400	250x250
SID4	400-1100	160x120
SID4-HR	400-1100	400x300
SID4-SWIR	900-1700	80x64
SID4-SWIR-H	R 900-1700	160x128
SID4-DWIR	3000-5000	

	Wavelength *	
2	(nm)	
	365	810
Select YOUR	405	850
D Cuba	530	940
2) K-Cube	625	1050
	0 740	1550
	780	3900
pe YOUR beam		

Beam Expander *	Focusing
Exit pupil diameter (mm)	System* F#
8 15 30 60 130	OR 0.6 1 1.6 2.5 5 10

Sha

+ Reference mirror (flat or sphere)

* more options upon request

ACCORDING TO YOUR SPECIFIC REQUIREMENTS



- Available from UV to IR
- Modules compatible with stand-alone use
- All measurement configurations: finite-finite, infinite-finite...
- Same modules fit for different setups

POWERFUL UNIQUE TECHNOLOGY

- High resolution
- Dedicated to large aberrations measurement
- Achromatic measurement: for any test wavelength
- Nanometric sensitivity



- Compact
- Designed for easy alignment
- Quick access to all results





ADAPTED TO ALL APPLICATIONS

• Telescope alignment and characterization



Concave mirror measurement



• Large diameter flat optics characterization: Filters, Windows, Polarizing optics



• Large diameter lens & objective measurement in any configuration

